

1. Scope

This specification is applies to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 5KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product compliant with the RoHS.)

2. Parts Number Code

С	1812	X	224	K	501	Т
(1)	(2)	(3)	(4)	(5)	(6)	(7)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

(2) Cmp Size		
Code	Length×Width	unit : mm(inch)
0201	0.60× 0.30	(.024× .011)
0402	1.00× 0.50	(.039× .020)
0603	1.60× 0.80	(.063× .031)
0805	2.00× 1.25	(.079× .049)
1206	3.20× 1.60	(.126× .063)
1210	3.20× 2.50	(.126× .098)
1808	4.60× 2.00	(.181× .079)
1812	4.60× 3.20	(.181× .125)
1825	4.60× 6.35	(.181× .250)
2208	5.70× 2.00	(.220× .197)
2211	5.70× 2.80	(.220× .110)
2220	5.70× 5.00	(.220× .197)
2225	5.70× 6.35	(.220× .250)

(3)Temperature Characteristics

Code	Temperature	Temperature	Temperature
	Characteristic	Range	Coefficient
N	NPO	-55°℃~+125°℃	30 ppm/°C
L	SL	-30°C ~+85°C	+350~-1000ppm
X	X7R	-55℃~+125℃	± 15%
В	X5R	-55°C ~+85°C	± 15%
S	X6S	-55°℃~+105°℃	± 22%
Υ	Y5V	-30°C ~+85°C	+22/-82%
Z	Z5U	+10°C∼+85°C	+22/-56%
Е	Y5U	-30°C ~+85°C	+22/-56%

(4)Capacitance unit :pico farads(pF)

` /	1 1
Code	Nominal Capacitance (pF)
5R0	5.0
120	12.0
151	150.0
222	2,200.0
103	10,000.0
224	220,000.0
105	1,000,000.0
106	10,000,000.0

^{**.} If there is a decimal point, it shall be expressed by an English capital letter R

(5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
В	± 0.10 pF	Less Than 10 pF
С	± 0.25 pF	(Include 10 pF)
D	± 0.50 pF	_
F	± 1.00 pF	_
F	± 1.00 %	More Than 10 pF
G	± 2.00 %	_
J	± 5.00 %	_
K	± 10.0 %	_
М	± 20.0 %	_
Z	+80/-20 %	

(6)Rated Voltage

Code	Rated Voltage (Vdc)
101	100
201	200
251	250
501	500
631	630
102	1,000
202	2,000
252	2,500
302	3,000
502	5,000

(7) Tapping

Туре
Tape & Reel
Bulk

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3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ance	Nominal Capacitance	
I	NPO / SL	Less Then 10 pF B (± 0.10 pF)		0.5,1,1.5,2,2.5,3	
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5	
			D (± 0.50 pF)	5,6,7,8,9,10	
			F (± 1.00 pF)	6,7,8,9,10	
		More Than 10 pF F (±1.00 %)		E-12, E-24 series	
			G (±2.00 %)		
			J (± 5.00 %)		
			K (± 10.0 %)		
П	X7R/X5R/X7E	K (± 10.0 %),	M (± 20.0 %)	E-3, E-6 series	
	Y5V	M (± 20.0 %), 2	Z(+80/-20%)	E- 3 series	
	Z5U				
	Y5U				

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0				2.2			4.7				
E- 6	1	.0	1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
I	NPO	NPO -55°C ~ +125°C	
	SL	-25℃ ~ +125℃	25 ℃
П	X7R	-55℃ ~ +125℃	25℃
	X5R	-55℃ ~ +85℃	25 ℃
	X6S	-55°C ~ +105°C	25 ℃
	Y5V	-30℃ ~ +85℃	25 ℃
	Z5U	+10℃ ~ +85℃	25 ℃
	Y5U	-30°C ~ +85°C	25 ℃
	Other	-25℃ ~ +85℃	25 ℃

5. Storage Condition

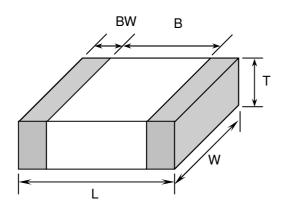
Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 6 months max.

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6. Dimensions

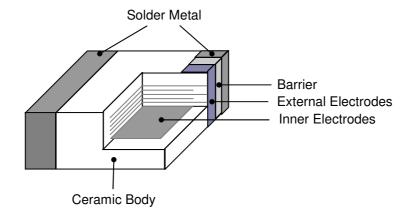
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	T	B (min)	BW (min)
1812	4.60± 0.30	3.20± 0.30	2.80± 0.20	2.50	0.30

6.2 Termination Type :





7. Performance

No.	Item		S	pecification	Test Condition		
1	Visua	ıl	No abnormal	exterior appearance	Visual inspection		
2	Dimens	ion	See Page 3		Visual inspection		
3	Insulati Resista	1 '			V≤500V, Rated Voltage V>500V, Applied 500Vdc Charge Time: 60sec. Is applied less than 50mA current.		
4	Capacitance	Class	Within The Spo	ecified Tolerance	Class I:		
		I NPO/SL Class	Within The Sn	ecified Tolerance	NPO/SL Capacitance Frequency Voltage		
		П			C≤100pF 1MHz±10% 1.0±0.2Vrms C>100pF 1KHz±10%		
5	Q	Class	More Than 30		Class Ⅱ:		
		I I		: Q≥400+20C	Frequency Voltage		
	Tan δ	NPO/SL	(C : Capacita		X7R 1KHz±10% 1.0±0.2Vrms		
	ian o	Class II	Char. X7R	Maximum 2.5%	Z5U/Y5U 1KHz±10% 1.0±0.2Vrms Perform a heat temperature at 150±5°C for		
		11	Z5U/Y5U	4.0%	30min. then place room temp. for 24±2hr.		
	Withstan	dina		breakdown or	V<500V : 200% Rated Voltage		
6	Voltag	-	mechanical b		500V≦V<1000V: 150% Rated Voltage		
		, -			1000 ≦ V :120% Rated Voltage		
					for 1~5 sec. Current is limited to less than		
					50mA.		
					Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc.		
7	Temperature	Class I	Char. Temp. F	Range Cap. Change(%)	Class I:		
	Capacitance		NPO -55°C ~+		[C2-C1/C1(T2-T1)] × 100%		
	Coefficient		SL -30°C∼+				
		Class	Char. Temp. F		(C2-C1)/C1 × 100%		
		П	X7R -55°C ~⊣		T1: Standard temperature (25°C) T2: Test temperature		
			Y5U -30°C ~	+85°C	C1:Capacitance at standard temperature(25°C)		
			Z 5U +10°C ~	+85°C +22% ~-56%	C2: Capacitance at test temperature (T2)		
8	Adhesive S			of peeling shall occur on	A 5N·f (≒0.5Kg·f) pull force shall be applied		
	of Termin	ation	the terminal el	ectrode.	for 10± 1 second.		
					₹ 5N·f		
					5111		
		П					
9	Resistance	Appear-	No mechanica	I damage shall be occur.	Bending shall be applied to the 1.0 mm with		
	to	ance		NI .	1.0 mm/sec. _R230 ↓		
	Flexure of Substrate	C-Meter	Capacitance C		→ Bending		
	oi Substrate		Char.	Cap. Change	Limit		
			NPO	≤ ± 5.0%	C Meter		
			SL	≤ ± 5.0%	< → < → 45±1mm 45±1mm		
			X7R	≤ ± 12.5%	40±111111		
			Y5U/Z5U	≦ ± 30.0%			



No.	Ite	m		Speci	fication			Test (Condition		
10	Solder	ability			he terminal surface			Temperature			
			is to be soldered newly, so metal part does not come out or dissolve.			Dip Time: 5 ± 0.5 sec. Immersing Speed: 25±10% mm/s					
			40031		or dissolve .		Solder : H63A				
				<i>→[[</i>			Flux	:Rosin			
	D '. I	A	NI				Prehea				
11	Resistance To	ance	NO ME	echanicai dar	nage shall occur.	Class		rs at			
	Soldering Heat	Capacit- ance		aracteristic	Cap. Change		eatme neasur	nt at 150 +0/-1 e.	0°C before	e initial	
	rioat	S. 100	Class (NPO/		Within ± 2.5% or ±0.25pFwhichever		Prehea	at : At 150± 10	℃ For 60~	120sec.	
			(141 0/	OL)	is larger of initial			older Tempera		0± 5℃	
			01	V7D	value			ne:10 ± 1sec		m/o	
			Class	X7R Z5U/Y5U	Within ± 10% Within ± 20%		Solder	sing Speed : 2 : H63A	3±10% IIII	11/5	
		Q			fied initial value		Flux	:Rosin			
		Class I Tan δ	To sati	sty the speci	fied initial value	M	1easur	e at room tem	perature at	ter cooling	for
		Class II	10 oati	ory and open	mod miliai valao			I : 24 ± 2 Ηοί		_	
		Insulation Resistance		sfy the spec	fied initial value		Class	i∏ : 48 ± 4 Hoι	ırs		
				sfy the spec	fied initial value						
12	Tempera ture	Appear- ance	No me	chanical dar	nage shall occur		Class ☐ capacitor shall be set for 48± 4 hours a room temperature after one hour heat treatmen				
	Cycle	Capacit-		aracteristic	Cap. Change	a	t 150 -	-0/-10 °C befor	e initial me	easure.	
		ance	Class (NPO/		Within ± 2.5% or ±0.25pFwhichever		Canac	itor shall be su	hiected to	five cycles	of
			(INFO)	SL)	is larger of initial			nperature cycl			Oi
			Class	X7R	value Within ± 7.5%		Step	Temp.(Time(min)	
			Uiass ∏	Z5U/Y5U	Within ± 20%		2	Min Rated Ter 25	np. +0/-3	30	_
		Q	To sati	sfy the spec	fied initial value		3	Max Rated Te	mp. +3/-0	30	
		Class I Tan δ	To ooti	of the appear	fied initial value		4	25	•	3	
		Class II	10 Sali	isiy ille speci	nieu iriiliai value	Ν		e at room temp	perature at	ter cooling	for
		Insulation		sfy the spec	fied initial value			i			
		Resistance						the capacitor	on P.C. bo	ard shown	in
		-					Fig 2.	before testing.			
13	Humidity	Appear- ance	No me	chanical dar	nage shall occur			capacitor sha temperature a			ırs
		Capacit-		racteristic	Cap. Change			nt at 150+0/-1			
		ance	Class		Within ± 5.0% or		neasur		C		
			(NPO/	SL)	±0.5pF whichever is larger of initial value			rature : 40± 2° re Humidity : 9		H	
			Class	X7R	Within ± 15%			me: 500 + 12		•	
			П		Within ± 30%		1			itau aaaliaa	f
		Q Class I		Γhan 30pF : (& Below: Ω ≥	Q ≧ 350 ≧ 275 + 2.5×C	IV		e at room temp s I :24 ± 2Hr		ter cooling	101
		Tan δ		nar.	<u>273 + 2.5xC</u> Maximum	1		s			
		Class II	X	7R	5.0%		وماطء	the conceite	on DC b-	ard share	in
		Inquilaties		/Y5U	5.0%			the capacitor before testing.		aru Snown	111
		Insulation Resistance	-		Ω whichever is		.g				
			2								

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No.	Ite	m	Specifi	cation		Test Condition		
14	High	Appear-	No mechanical dam	age shall occur		ass	_	
	•	ance		T		ollowing table) is app		
	Load	Capacit-	Characteristic	Cap. Change	-	maximum operation temperature ±3℃ then		
		ance	Class I	Within ±3.0% or			urs at room temperature	
			(NPO/SL)	± 0.3pFwhichever is larger		d the initial measurer	ment shall be	
			Class X7R	Within ± 15%	1	conducted.		
			II Z5U/Y5U	Within ± 30%	Ap	oplied Voltage :		
		Q	More Than 30pF : Q	≥ 350		Rated Voltage	Applied Voltage	
		Class I	30pF & Below:Q ≥ 3			V≤250Vdc	150%Rated Voltage	
		Tan δ	Char.	maximum		Less Than 1KVdc	120%Rated Voltage	
		Class II	X7R	5.0%	-	More Than	100%Rated Voltage	
		Inquiation	Z5U/Y5U 1,000MΩ or 50/C Ω	5.0%	-	1KVdc(include 1KV)	100%haleu vollage	
		Resistance	-	(C in Farad)				
		licoiotarioc	Sinanci.	(O III I alaa)		1210/100V capacitance more than 1.0uF applied voltage of 120% rated voltage Temperature : max. operation temperature Test Time : 1000 +12/-0Hr		
						rrent Applied: 50 m/		
							erature after cooling for	
					Cla	ass I : 24 ± 2 Hours		
						ass II: 48 ± 4 Hours		
15	Vibration	Appear-	No mechanical dam	age shall occur			n P.C. Board shown in	
		ance	01		F	ig 2. before testing.		
		Capacit-	Characteristic	Cap. Change		ibrata tha aspasitar u	with amplitude of 1 5mm	
		ance	Class I (NPO/SL)	Within ± 2.5% or ± 0.25pFwhichever			vith amplitude of 1.5mm uencies from 10Hz to	
			(INI O/SL)	is larger		5Hz and back to 10H		
			Class X7R	Within ± 7.5%				
			II Z5U/Y5U	Within ± 20%			each in 3perpendicular	
		Q	To satisfy the specifi	ed initial value	dir	ections.		
		Class I						
		Tan δ	To satisfy the specifi	ed initial value				
		Class II	Ta ankata da a a a a a	and installation of the	-			
			To satisfy the specifi	ea initiai value				
		Resistance						

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Fig.1
P.C. Board for Bending Strength Test

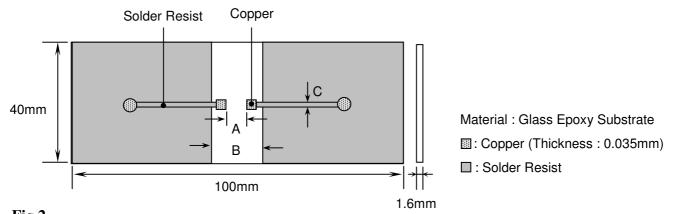
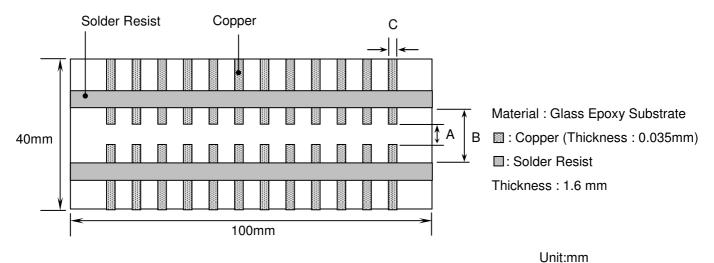


Fig.2 Test Substrate



Type	Α	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

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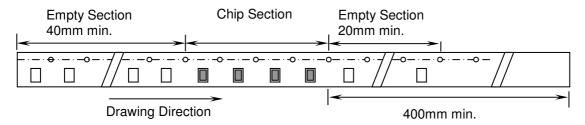


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/	0805
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	1210/1808		
Material	T≦0.90mm	0.90mm < T ≤ 1.25mm	T>1.25mm	T≦1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel	3000 pcs/Reel	2000 pcs/Reel

Tape	1812/1825	/2211/2220	22	2225		
Material	T≦2.20mm T>2.20mm		T≦2.20mm	T≦2.20mm		
Paper	NA	NA	NA	NA	NA	
Plastic	1000 pcs/Reel	700 pcs/Reel	1000 pcs/Reel	400 pcs/Reel	1000 pcs/Reel	

NA: Not Available

8.4 Cover Tape Reel Off Force

9.4.1 Peel-Off Force

 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

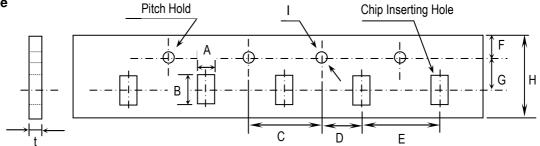
9.4.2 Measure Method



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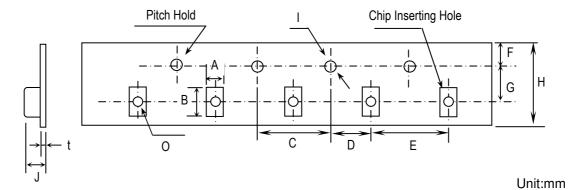


Unit:mm

TYPE	Α	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



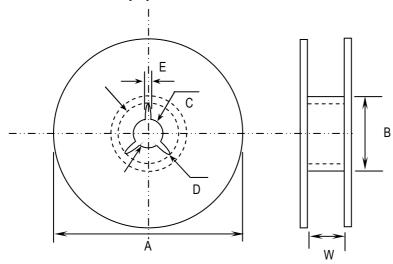
Type	Α	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	0.15 min.
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	Α	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						

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Precautionary Notes:

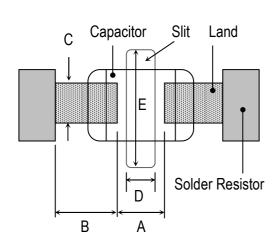
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 6 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

2.1 Size and recommend land dimensions for reflow soldering .

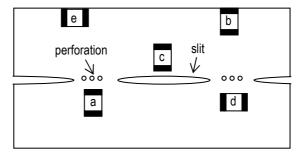


EIA Codo	Chip (mm)		Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		1
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		1
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		1
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.

Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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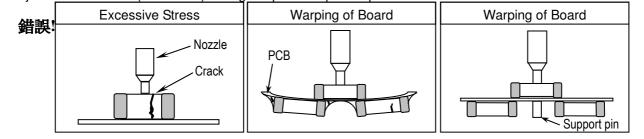


2.3 Layout Recommendation

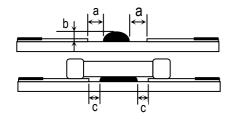
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder Adhesive PCB Solder Land	Chassis Excessive Solder a	Solder Land
Recommendation	Chip Solder Resist Adhesive PCB Solder Land	Solder Resist $\alpha > \beta$	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



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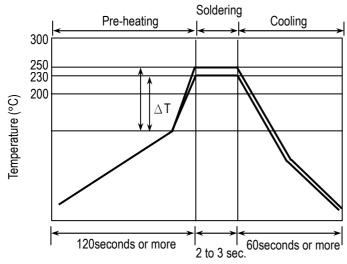


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to $250\,^{\circ}$ C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	$\Delta T \le 100 \sim 130 \text{ max}.$

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

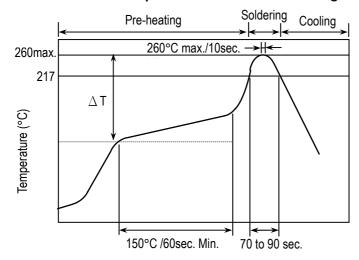
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed $3\,^{\circ}\text{C/Sec}$.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



※ The cycles of soldering : Twice (max.)

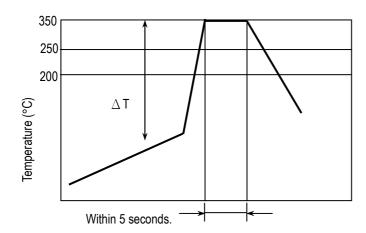
Soldering Method	Change in Temp.(°C)	
1206 and Under	∆T ≦ 190 °C	
1210 and Over	∆T ≦ 130 °C	

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 190 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

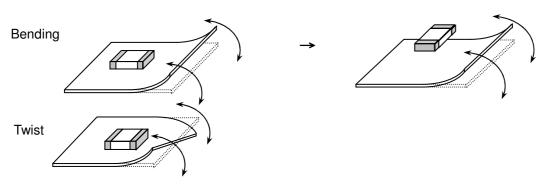
- 1) Selection of the soldering iron tip
 - The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.
- 2) recommended solder iron condition
 - a.) Preheat the substrate to (60 ℃ to 120 ℃) on a hot plate. Note that due to the heat loss, the actual setting of the hot plate may have to be higher. (For example 100 ℃ to 150 ℃)
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 ℃., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack





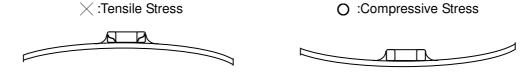
5.2 There is a potential of crack if board is warped due to excessive load by check pin



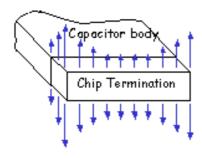
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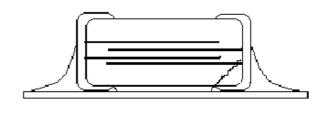


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



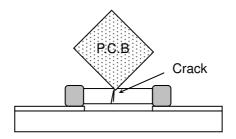


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 75% RH. The shelf life of capacitors is 6 months.

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